What is claimed is:

- 1 1. A method for use in assembling a microelectronic circuit package, comprising:
- 2 providing a package substrate;
- applying a polymer material to a surface of said package substrate;
- 4 attaching pins to said package substrate, through said polymer material, by
- 5 solder reflow; and
- 6 allowing said polymer material to cure about solder joints associated with said
- 7 pins.
- 1 2. The method of claim 1, wherein:
- 2 attaching pins includes placing solder elements in the polymer material in
- 3 desired pin locations.
- 1 3. The method of claim 2, wherein:
- 2 said solder elements include solder balls.
- 1 4. The method of claim 2, wherein:
- 2 attaching pins includes pressing a pin toward said package substrate at the
- 3 location of a solder element.
- 1 5. The method of claim 2, wherein:
- 2 attaching pins includes using a jig to press multiple pins toward said package
- 3 substrate at the locations of solder elements.
- 1 6. The method of claim 1, wherein:
- 2 applying a polymer material includes screen printing said material on said
- 3 surface.





- 1 7. The method of claim 1, wherein:
- 2 attaching pins to said package substrate includes placing said pins in a jig and
- 3 applying pressure to said jig at a temperature that equals or exceeds a melting
- 4 temperature of the pin solder so that the pins are pressed through the polymer material.
- 1 8. The method of claim 1, wherein:
- 2 said polymer material includes a no flow material.
- 1 9. The method of claim 1, wherein:
- 2 said polymer material has fluxing capabilities.
- 1 10. A method for use during fabrication of a microelectronic device package,
- 2 comprising:
- 3 providing a package substrate having a plurality of contact pads on a surface
- 4 thereof;
- 5 attaching pins to said plurality of contact pads by solder reflow; and
- applying an encapsulation material about solder joints associated with said pins,
- 7 said encapsulation material to maintain a location of said pins on said package substrate
- 8 during subsequent high temperature processing.
- 1 11. The method of claim 10, wherein attaching pins includes:
- 2 placing said pins in a jig;
- applying solder to at least one of the following: said pins and said contact pads;
- 4 aligning said jig with said package substrate; and
- 5 applying pressure to said jig at a temperature that equals or exceeds a melting
- 6 temperature of said solder.
- 1 12. The method of claim 10, wherein:
- applying an encapsulation material includes applying a no flow material.

- 1 13. The method of claim 10, wherein:
- 2 said encapsulation material includes at least one of the following: an epoxy-
- 3 based material and a polyimide-based material.
- 1 14. A substrate for use in a microelectronic circuit package, comprising:
- a plurality of pin contact pads on a first surface of said substrate;
- a plurality of pins soldered to pin contact pads on said first surface of said
- 4 substrate; and
- an encapsulation material surrounding solder joints associated with said
- 6 plurality of pins, said encapsulation material preventing movement of pins when said
- 7 substrate is subjected to high temperatures.
- 1 15. The substrate of claim 14, wherein:
- 2 said encapsulation material includes a polymer material.
- 1 16. The substrate of claim 14, wherein:
- 2 said encapsulation material includes a no flow material.
- 1 17. The substrate of claim 14, wherein:
- 2 said encapsulation material includes at least one of the following: an epoxy-
- 3 based material and a polyimide-based material.
- 1 18. A microelectronic device comprising:
- a package substrate having pin contact pads on a first surface thereof;
- a plurality of pins soldered to said pin contact pads on said first surface of said
- 4 package substrate;
- an encapsulation material surrounding solder joints associated with said
- 6 plurality of pins, said encapsulation material preventing movement of pins when said
- 7 microelectronic device is subjected to high temperatures; and

- 8 a microelectronic die connected to said package substrate, said microelectronic
- 9 die having bond pads that are conductively coupled to said pins through said package
- 10 substrate.
- 1 19. The microelectronic device of claim 18 wherein:
- 2 said microelectronic die is connected to said package substrate using a lead free
- 3 solder having a relatively high melting temperature.
- 1 20. The microelectronic device of claim 18 wherein:
- 2 said encapsulation material includes a polymer material.
- 1 21. The microelectronic device of claim 18 wherein:
- 2 said encapsulation material includes a no flow material.
- 1 22. The microelectronic device of claim 18 wherein:
- 2 said encapsulation material includes at least one of the following: an epoxy-
- 3 based material and a polyimide-based material.